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U. S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
N1	1.	5,546,408	8/13/96	Keller	371	27	

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N1	2.	K. Dwarakanath et al; *Universal Fault Simulation Using Fault Tuples;* Annual ACM IEEE Design Automation Conference; Proceedings of the 37th conference on Design automation; June 5-9, 2000, Los Angeles, CA USA pp 786-789.
N1	3.	Rao Desineni et al; *Universal Test Generation Using Fault Tuples; ITC* International Test Conference (31st: 2000: Atlantic City, NJ) Proceedings International Test Conference 2000: October 3-5, 200, New Atlantic City Convention Center, Atlantic City, NJ, USA; pp 812-819.
N1	4.	TestBench, Library Data Reference, Ninth Edition; Version 2000, IBM Corporation; Endicott, NY 13760; pp 170-181 and 177-183.
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N1	6.	J. Khare et al; *Fault Characterization of Standard Cell Libraries Using Inductive Contamination Analysis (ICA)* 14th VLSI Test Symposium - 1996 pp 405-413.

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	10.	J. Paul Roth; *Diagnosis of Automata Failures: A Calculus and a Method;* IBM Journal, July 1966, pp 278-291.
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